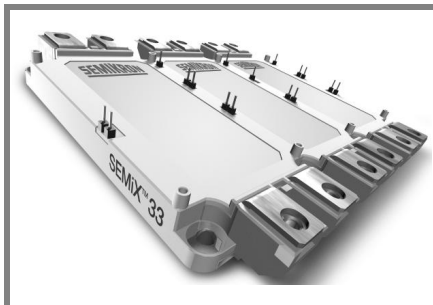


SEMiX 303GD12T4c



SEMiX® 33c

Trench IGBT Modules

SEMiX 303GD12T4c

Target Data

Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability

Typical Applications

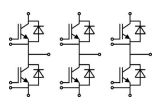
- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$

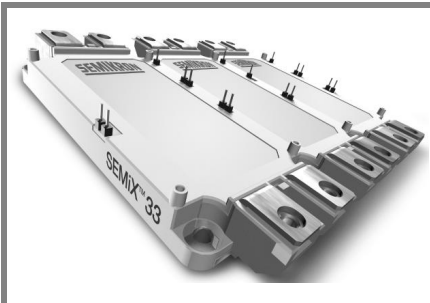
Absolute Maximum Ratings		$T_{case} = 25^\circ\text{C}$, unless otherwise specified			
Symbol	Conditions	Values			Units
IGBT					
V_{CES}	$T_j = 25^\circ\text{C}$	1200			V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	465		A
		$T_c = 80^\circ\text{C}$	360		A
I_{CRM}	$I_{CRM}=3 \times I_{Cnom}$	900			A
V_{GES}		± 20			V
t_{psc}	$V_{CC} = 600\text{ V}; V_{GE} \leq 20\text{ V}; T_j = 150^\circ\text{C}$ $V_{CES} < 1200\text{ V}$	10			μs
Inverse Diode					
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	340		A
		$T_c = 80^\circ\text{C}$	255		A
I_{FRM}	$I_{FRM}=3 \times I_{Fnom}$	900			A
Module					
$I_{t(RMS)}$		600			A
T_{vj}		- 40 ... + 175			$^\circ\text{C}$
T_{stg}		- 40 ... + 125			$^\circ\text{C}$
V_{isol}	AC, 1 min.	4000			V

Characteristics		$T_{case} = 25^\circ\text{C}$, unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
IGBT					
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 12\text{ mA}$	5	5,8	6,5	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}$				$T_j = 25^\circ\text{C}$ mA
V_{CE0}					$T_j = 25^\circ\text{C}$ V
					$T_j = 150^\circ\text{C}$ V
r_{CE}	$V_{GE} = 15\text{ V}$				$T_j = 25^\circ\text{C}$ m Ω
					$T_j = 150^\circ\text{C}$ m Ω
$V_{CE(sat)}$	$I_{Cnom} = 300\text{ A}, V_{GE} = 15\text{ V}$				$T_j = 25^\circ\text{C}_{chiplev.}$ V
					$T_j = 150^\circ\text{C}_{chiplev.}$ V
C_{ies}	$V_{CE} = 25, V_{GE} = 0\text{ V}$				18,6 nF
C_{oes}					1,2 nF
C_{res}					1,1 nF
Q_G	$V_{GE} = -8 \dots +15\text{ V}$				1700 nC
R_{Gint}	$T_j = 25^\circ\text{C}$				2,5 Ω
$t_{d(on)}$	$R_{Gon} = \Omega$	$V_{CC} = V$ $I_{Cnom} = A$ $T_j = 150^\circ\text{C}$			33 ns
t_r					
E_{on}	$R_{Goff} = \Omega$			33 mJ	
$t_{d(off)}$					
t_f					
E_{off}			33 mJ		
$R_{th(j-c)}$	per IGBT				0,095 K/W



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Typical Applications

- AC inverter drives
- UPS
- Electronic Welding

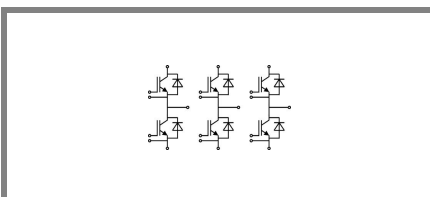
Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$

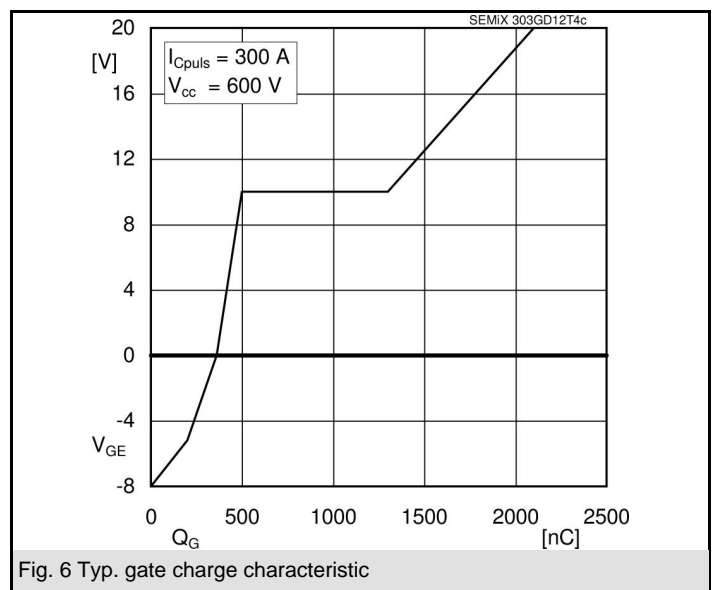
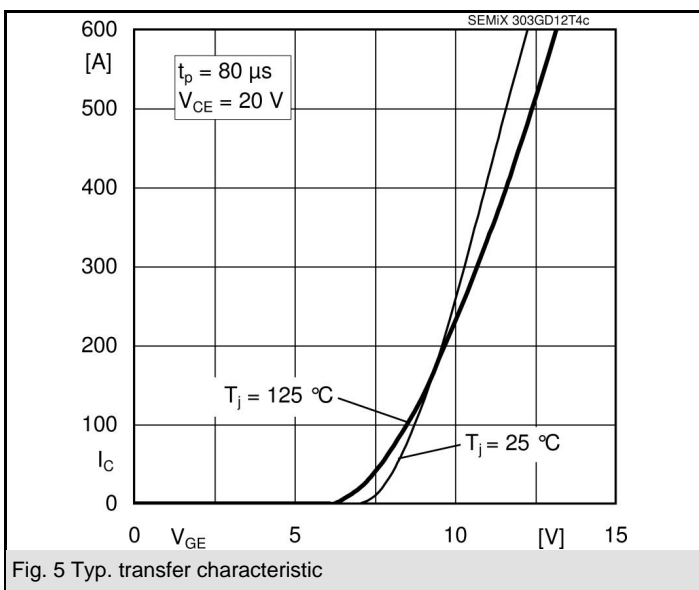
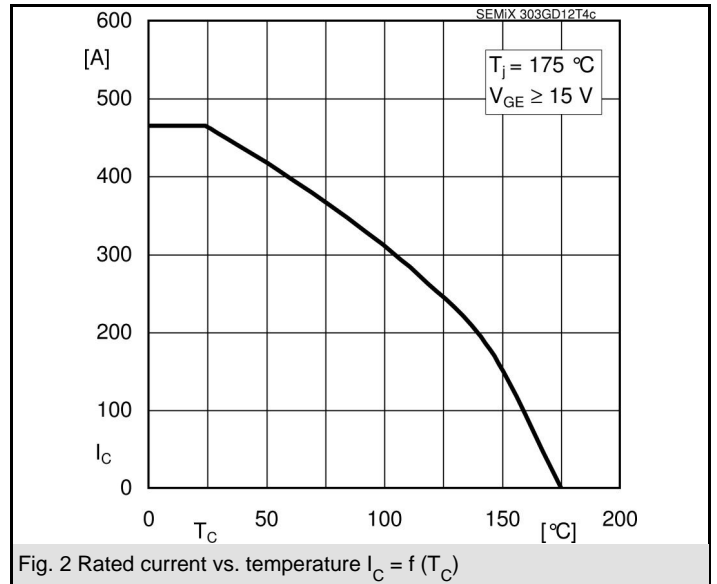
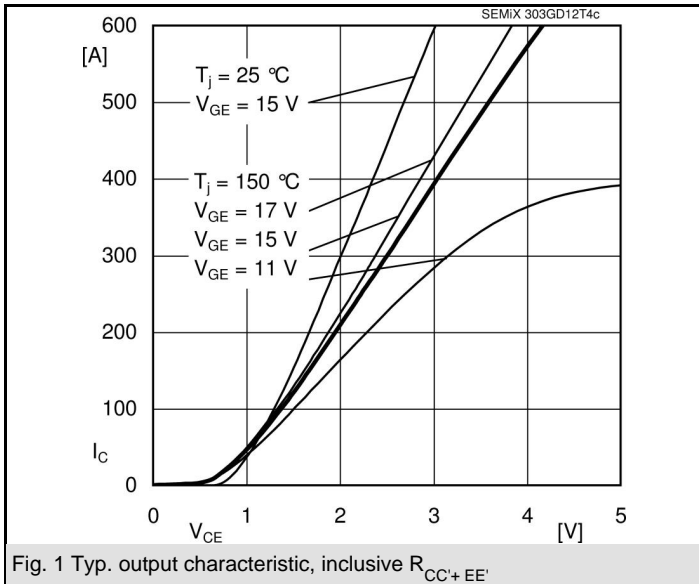
Characteristics			min.	typ.	max.	Units
Inverse Diode						
$V_F = V_{EC}$	$I_{Fnom} = 300 \text{ A}; V_{GE} = 0 \text{ V}$	$T_j = 25^\circ\text{C}_{\text{chiplev.}}$		2,2	2,5	V
		$T_j = 150^\circ\text{C}_{\text{chiplev.}}$		2,1	2,45	V
V_{F0}		$T_j = 25^\circ\text{C}$		1,3	1,5	V
		$T_j = 150^\circ\text{C}$		0,9	1,1	V
r_F		$T_j = 25^\circ\text{C}$		3	3,3	mΩ
		$T_j = 150^\circ\text{C}$		4	4,5	mΩ
I_{RRM}	$I_{Fnom} = 300 \text{ A}$	$T_j = 150^\circ\text{C}$				A
Q_{rr}						μC
E_{rr}	$V_{GE} = -15 \text{ V}; V_{CC} = 600 \text{ V}$			22,5		mJ
$R_{th(j-c)D}$	per diode				0,18	K/W
Module						
L_{CE}				20		nH
$R_{CC'+EE'}$	res., terminal-chip	$T_{case} = 25^\circ\text{C}$		0,7		mΩ
		$T_{case} = 125^\circ\text{C}$		1		mΩ
$R_{th(c-s)}$	per module			0,014		K/W
M_s	to heat sink (M5)			3	5	Nm
M_t	to terminals (M6)			2,5	5	Nm
w					900	g
Temperature sensor						
R_{100}	$T_c = 100^\circ\text{C}$ ($R_{25} = 5 \text{ k}\Omega$)			0,493±5%		kΩ
$B_{100/125}$	$R(T) = R_{100} \exp[B_{100/125} (1/T - 1/T_{100})]$; $T[\text{K}]$			3550±2%		K

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.



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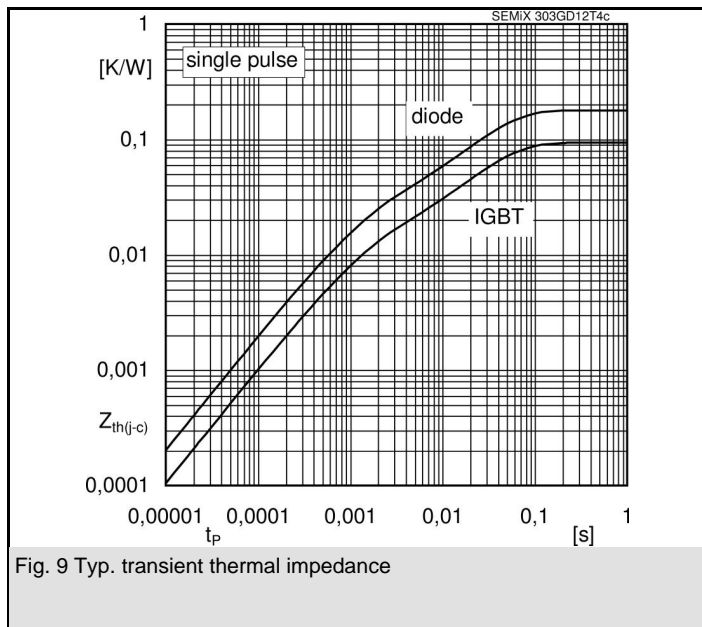


Fig. 9 Typ. transient thermal impedance

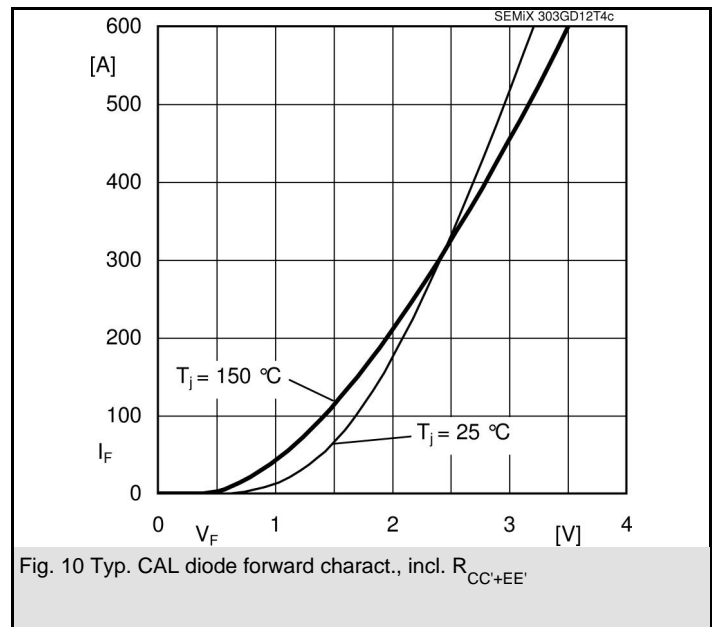
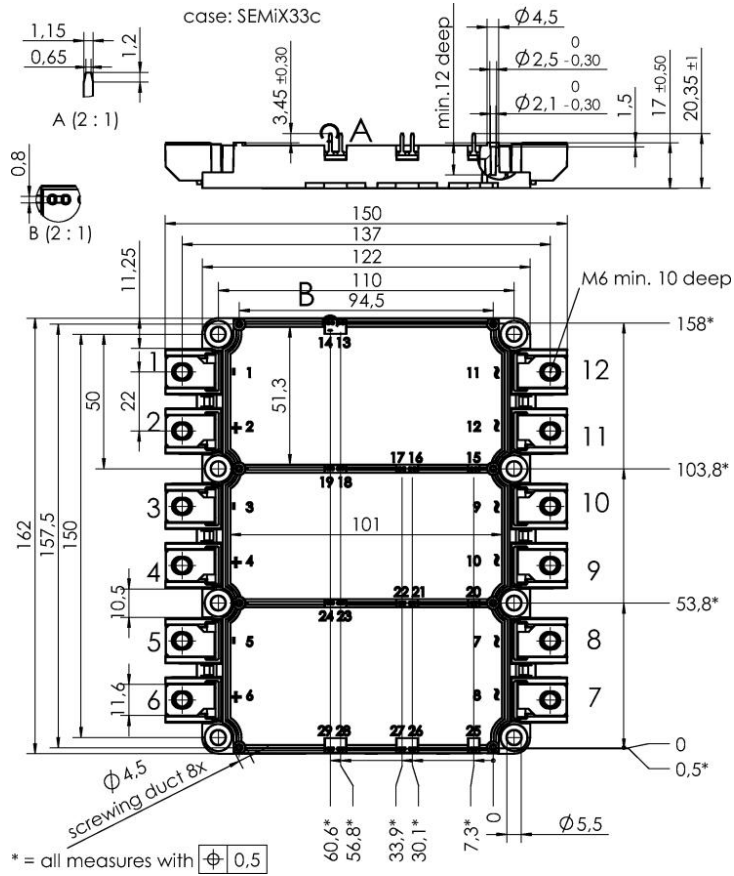


Fig. 10 Typ. CAL diode forward charact., incl. $R_{CC+EE'}$

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Case SEMiX 33c

